July 2014



FCH170N60 N-Channel SuperFET[®] II MOSFET 600 V, 22 A, 170 mΩ

Features

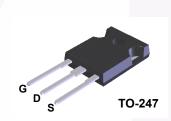
- 650 V @T_J = 150°C
- Typ. R_{DS(on)} = 150 mΩ
- Ultra Low Gate Charge (Typ. Q_g = 42 nC)
- Low Effective Output Capacitance (Typ. C_{oss(eff.)} = 190 pF)
- 100% Avalanche Tested
- RoHS Compliant

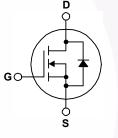
Applications

- Telecom / Sever Power Supplies
- Industrial Power Supplies
- AC-DC Power Supply

Description

SuperFET[®] II MOSFET is Fairchild Semiconductor's brand-new high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This advanced technology is tailored to minimize conduction loss, provide superior switching performance, and withstand extreme dv/dt rate and higher avalanche energy. Consequently, SuperFET II MOSFET is suitable for various AC/DC power conversion for system miniaturization and higher efficiency.





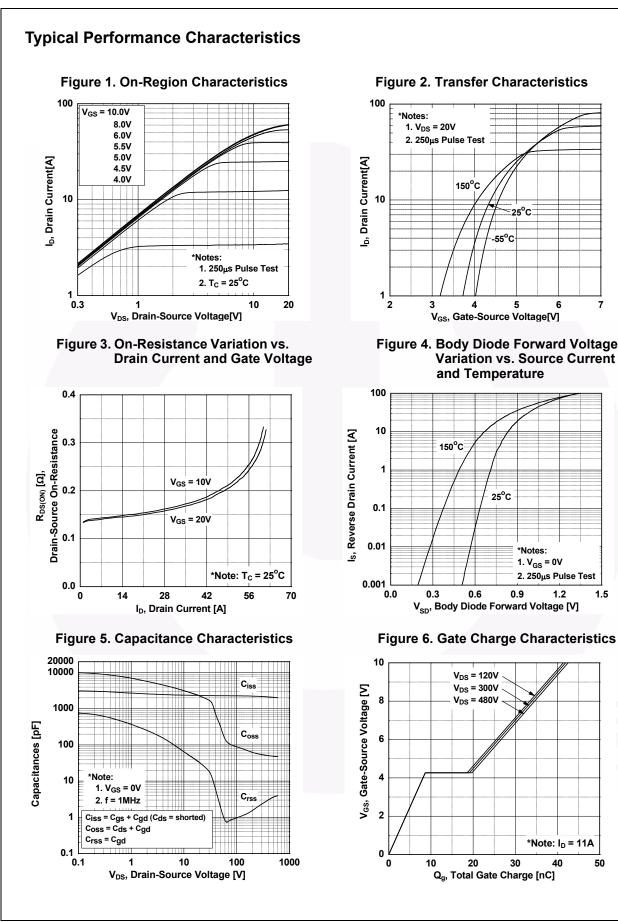
Absolute Maximum Ratings T_C = 25°C unless otherwise noted.

Symbol	Parameter			FCH170N60	Unit	
V _{DSS}	Drain to Source Voltage			600	V	
V _{GSS}	Cata ta Cauraa Maltaga	- DC		±20	v	
	Gate to Source Voltage	- AC	- AC			
ID	Drain Current	- Continuous (T _C = 25 ^o C)		22	Α	
		- Continuous (T _C = 100 ^o C)		14	A	
I _{DM}	Drain Current	- Pulsed	(Note 1)	66	А	
E _{AS}	Single Pulsed Avalanche Energy (No		(Note 2)	525	mJ	
I _{AR}	Avalanche Current		(Note 1)	5	А	
E _{AR}	Repetitive Avalanche Energy		(Note 1)	2.27	mJ	
du/dt	MOSFET dv/dt (Note 3)			100	Maa	
dv/dt	Peak Diode Recovery dv/dt			20	V/ns	
P _D	Dewer Dissignation	(T _C = 25 ^o C)		227	W	
	Power Dissipation	- Derate above 25°C		1.82	W/ ^o C	
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C		
TL	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 Seconds			300	°C	

Thermal Characteristics

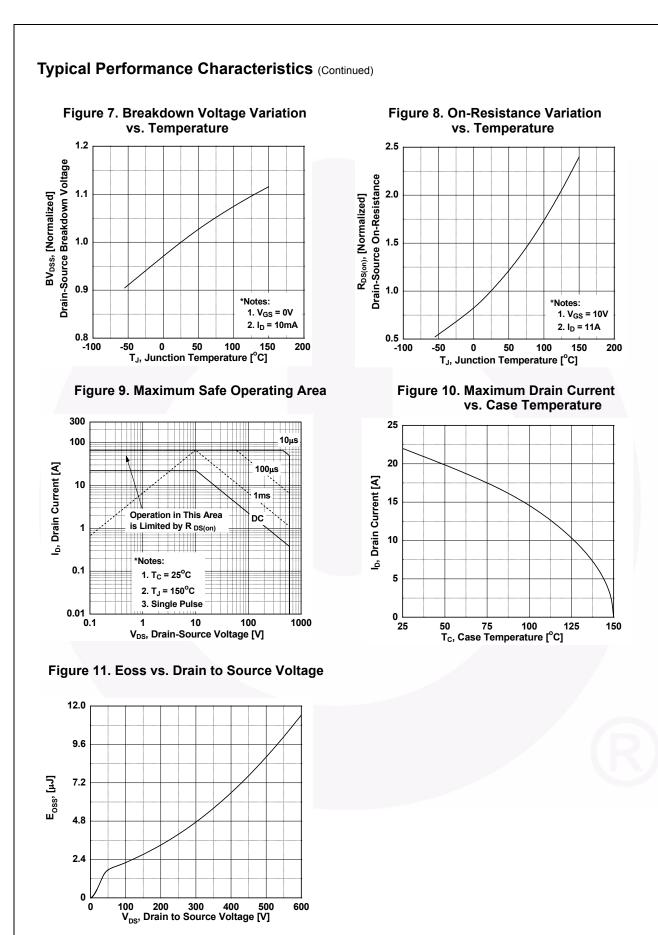
Symbol	Parameter	FCH170N60		
$R_{ ext{ heta}JC}$	Thermal Resistance, Junction to Case, Max.	0.55	°C/W	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max.	40	- 0/00	

Device Marking Device I		Pacl	ckage Reel Size T		Та	ape Widt	h	Quanti	ty
<u> </u>		TO-	-247	-		-		30	
l Chara	acteristics T _c = 28	5ºC unless	otherwise r	oted.			· ·		
	Parameter			Test Conditions		Min.	Тур.	Max.	Unit
teristics	5								
V _{DSS} Drain to Source Breakdown Voltage BV _{DSS} Breakdown Voltage Temperature		ane	$I_{D} = 10 \text{ mA}, V_{GS} = 0 \text{ V}, T_{J} = 25^{\circ}\text{C}$			600	-	-	V
		•	$I_{\rm D}$ = 10 mA,V _{GS} = 0 V, T _J = 150°C			650	-	-	V
	o .		$I_D = 10 \text{ mA}, \text{ Referenced to } 25^{\circ}\text{C}$			-	0.67	-	V/ºC
DSS Zero Gate Voltage Drain Current GSS Gate to Body Leakage Current		t	V_{DS} = 480 V, V_{GS} = 0 V, T_C = 125°C				-	1	μΑ
						-	1.2	-	
Gate to	Gate to Body Leakage Current		$V_{GS} = \pm 20$	$V, V_{DS} = 0 V$		<u> </u>	-	±100	nA
teristics	;								T
Gate Th	reshold Voltage					2.5	-	3.5	V
Static Dr	rain to Source On Resist	tance				-	150	170	mΩ
Forward	orward Transconductance		V _{DS} = 20 V, I _D = 11 A			-	17	-	S
haracte	ristics								
Input Ca	pacitance		V _{DS} = 380 V, V _{GS} = 0 V f = 1 MHz		-	2150	2860	pF	
Output C	Capacitance				-	60	80	pF	
Reverse	Transfer Capacitance				-	2.65	-	pF	
Effective	Output Capacitance		V _{DS} = 0 V	' to 480 V, V _{GS} =	0 V	-	190	-	pF
Total Ga	te Charge at 10V		V _{DS} = 380) V, I _D = 11 A,		-	42	55	nC
Gate to S	Source Gate Charge				-	-	9	-	nC
Gate to I	Drain "Miller" Charge		(Note 4)		-	11	-	nC	
Equivale	ent Series Resistance		f = 1 MHz			-	0.95	-	Ω
Charact	eristics								
Turn-On	Delay Time		V_{DD} = 380 V, I _D = 11 A, V_{GS} = 10 V, R _g = 4.7 Ω		•	21	50	ns	
Turn-On	Rise Time				-	12	35	ns	
Turn-Off	Delay Time					-	55	120	ns
Turn-Off	Fall Time				(Note 4)	-	3.8	18	ns
ce Diod	e Characteristics								
		ource Diod	de Forward (Current		-	-	22	Α
Maximum Pulsed Drain to Source Diode		e Diode Fo	Forward Current		-	-	66	Α	
Drain to	Source Diode Forward V	/oltage	V _{GS} = 0 V, I _{SD} = 11 A		-	-	1.2	V	
Reverse	Recovery Time		$V_{GS} = 0 V, I_{SD} = 11 A,$ $dI_F/dt = 100 A/\mu s$		-	346	-	ns	
Reverse	Recovery Charge				-	6.2	-	μC	
	teristics Drain to Breakdo Coefficie Zero Ga Gate to teristics Gate Th Static Dr Forward haracte Input Ca Output C Reverse Effective Total Ga Gate to 1 Equivale Charact Turn-On Turn-Off Turn-Off Turn-Off Ce Diod	Parameter Parameter teristics Drain to Source Breakdown Volt Breakdown Voltage Temperature Coefficient Zero Gate Voltage Drain Curren Gate to Body Leakage Current teristics Gate Threshold Voltage Static Drain to Source On Resis Forward Transconductance haracteristics Input Capacitance Output Capacitance Reverse Transfer Capacitance Effective Output Capacitance Total Gate Charge at 10V Gate to Drain "Miller" Charge Equivalent Series Resistance Characteristics Turn-On Delay Time Turn-Off Delay Time Turn-Off Fall Time Ce Diode Characteristics Maximum Continuous Drain to Source	Parameter teristics Drain to Source Breakdown Voltage Breakdown Voltage Temperature Coefficient Zero Gate Voltage Drain Current Gate to Body Leakage Current teristics Gate Threshold Voltage Static Drain to Source On Resistance Forward Transconductance haracteristics Input Capacitance Qutput Capacitance Qutput Capacitance Gate to Dource Gate Charge Gate to Drain "Miller" Charge Equivalent Series Resistance Characteristics Turn-On Delay Time Turn-Off Delay Time Turn-Off Fall Time Ce Diode Characteristics Maximum Continuous Drain to Source Diode Forward Voltage Reverse Recovery Time	ParameterteristicsDrain to Source Breakdown Voltage $I_D = 10 \text{ m/s}$ $I_D = 10 \text{ m/s}$ 	teristicsImage: Drain to Source Breakdown VoltageI_D = 10 mA, V_{GS} = 0 V, T_J = I_D = 10 mA, V_{GS} = 0 V, T_J = I_D = 10 mA, V_{GS} = 0 V, T_J = I_D = 10 mA, V_{GS} = 0 V, V_{DS} = 480 V, V_{DS} = 480 V, V_{DS} = 600 V, V_{DS} = 0 VGate to Body Leakage CurrentV_{GS} = ±20 V, V_{DS} = 0 VteristicsImage: Colspan="2">Colspan="2"Colspan=	ParameterTest ConditionsteristicsDrain to Source Breakdown Voltage $I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}, T_J = 25^{\circ}\text{C}$ Breakdown Voltage Temperature Coefficient $I_D = 10 \text{ mA}, \text{V}_{GS} = 0 \text{ V}, T_J = 150^{\circ}\text{C}$ Breakdown Voltage Drain Current $I_D = 10 \text{ mA}, \text{Referenced to } 25^{\circ}\text{C}$ Zero Gate Voltage Drain Current $V_{DS} = 600 \text{ V}, V_{GS} = 0 \text{ V}$ Gate to Body Leakage Current $V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$ teristicsGate Threshold Voltage $V_{GS} = 10 \text{ V}, I_D = 11 \text{ A}$ Forward Transconductance $V_{DS} = 20 \text{ V}, I_D = 11 \text{ A}$ Forward Transconductance $V_{DS} = 380 \text{ V}, V_{GS} = 0 \text{ V}$ factorapacitance $V_{DS} = 380 \text{ V}, V_{GS} = 0 \text{ V}$ fact charge transfer Capacitance $V_{DS} = 380 \text{ V}, I_D = 11 \text{ A}$ haracteristicsInput Capacitance $V_{DS} = 380 \text{ V}, I_D = 11 \text{ A}$ fact to Source Gate Charge $V_{DS} = 380 \text{ V}, I_D = 11 \text{ A}$ Gate to Source Gate Charge $V_{CS} = 10 \text{ V}$ Gate to Drain "Miller" Charge $(Note 4)$ Equivalent Series Resistance $f = 1 \text{ MHz}$ CharacteristicsTurn-On Rise Time $V_{DD} = 380 \text{ V}, I_D = 11 \text{ A},$ Turn-Off Fall Time $V_{OS} = 10 \text{ V}, R_g = 4.7 \Omega$ Turn-Off Fall Time $(Note 4)$ Explore CharacteristicsMaximum Continuous Drain to Source Diode Forward CurrentMaximum Pulsed Drain to Source Diode Forward CurrentMaximum Pulsed Drain to Source Diode Forward CurrentMaximum Pulsed Drain to Source Diode F	$\begin{tabular}{ c c c c } \hline Parameter & Test Conditions & Min. \\ \hline teristics \\ \hline teristics \\ \hline \begin{tabular}{ c c c c } \hline Parameter & I_D = 10 mA, V_{GS} = 0 V, T_J = 25^\circ C & 600 \\ \hline I_D = 10 mA, V_{GS} = 0 V, T_J = 150^\circ C & 650 \\ \hline I_D = 10 mA, Referenced to 25^\circ C & - \\ \hline V_{DS} = 600 V, V_{GS} = 0 V, T_C = 125^\circ C & - \\ \hline V_{DS} = 480 V, V_{GS} = 0 V, T_C = 125^\circ C & - \\ \hline Certistics & V_{GS} = 480 V, V_{DS} = 0 V, T_C = 125^\circ C & - \\ \hline Certistics & V_{GS} = 480 V, V_{DS} = 0 V, T_C = 125^\circ C & - \\ \hline Certistics & V_{GS} = 10 V, I_D = 11 A & - \\ \hline Porward Transconductance & V_{GS} = 10 V, I_D = 11 A & - \\ \hline haracteristics & V_{DS} = 380 V, V_{GS} = 0 V & - \\ \hline Coutput Capacitance & V_{DS} = 380 V, V_{GS} = 0 V & - \\ \hline Cotal Gate Charge at 10V & V_{DS} = 380 V, I_D = 11 A, & - \\ \hline Characteristics & V_{GS} = 10 V & V_{OS} = 10 V & - \\ \hline Cata to Source Cate Charge & V_{GS} = 10 V & - \\ \hline Cata to Source Cate Charge & V_{GS} = 10 V & - \\ \hline Cata to Source Cate Charge & V_{GS} = 10 V & - \\ \hline Characteristics & V_{DS} = 380 V, I_D = 11 A, & - \\ \hline Characteristics & V_{DS} = 10 V & V_{DS} = 380 V, I_D = 11 A, & - \\ \hline Characteristics & V_{DS} = 10 V & V_{CS} = 10 V & - \\ \hline Curn-Of Delay Time & V_{DS} = 380 V, I_D = 11 A, & - \\ \hline Turn-On Delay Time & V_{CS} = 10 V, R_g = 4.7 \Omega & - \\ \hline Turn-Off Fall Time & V_{DS} = 380 V, I_D = 11 A, & - \\ \hline Ce Diode Characteristics & V_{CS} = 0 V I_{SS} = 10 V & - \\ \hline Cate I former & V_{CS} = 0 V, I_{SD} = 11 A, & - \\ \hline Characteristics & V_{CS} = 10 V, R_g = 4.7 \Omega & - \\ \hline Turn-Off Fall Time & V_{CS} = 0 V, I_{SD} = 11 A, & - \\ \hline Park to Source Diode Forward Current & - \\ \hline Maximum Continuous Drain to Source Diode Forward Current & - \\ \hline Train to Source Diode Forward Current & - \\ \hline Park to Source Diode Forward Current & - \\ \hline Cate Diode Characteristics & V_{CS} = 0 V, I_{SD} = 11 A, & - \\ \hline Character = \\ \hline Cate Diode Characteristics & V_{CS} = 0 V, I_{SD} = 11 A, & - \\ \hline Cate Diode Characteristics & V_{CS} = 0 V, I_{SD} = 11 A, & - \\ \hline Cate Diode Characteristics & V_{CS} = 0 V, I_{$	$\begin{tabular}{ c c c c c } \hline Parameter & Test Conditions & Min. 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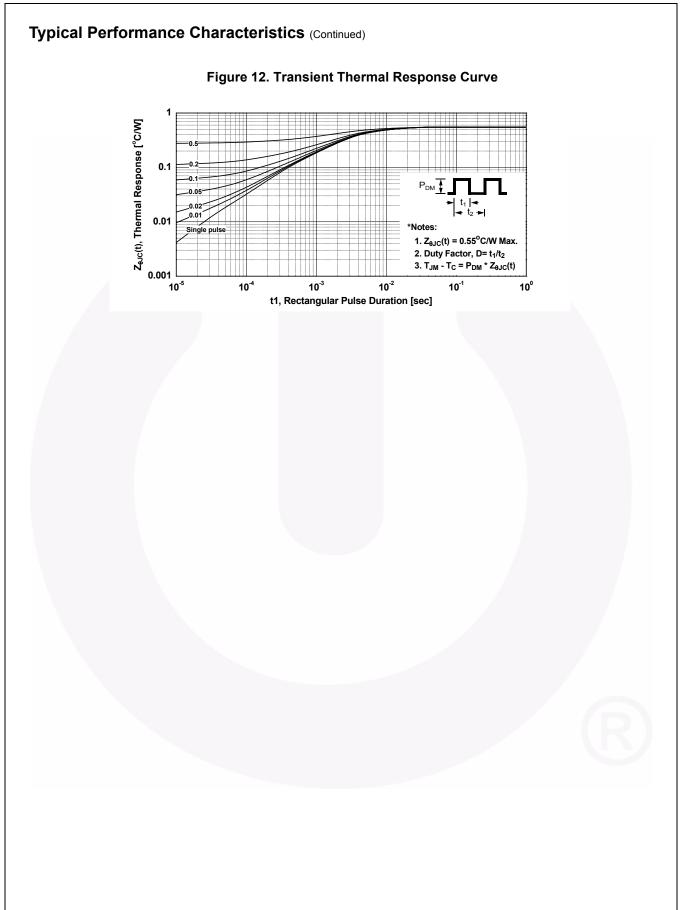
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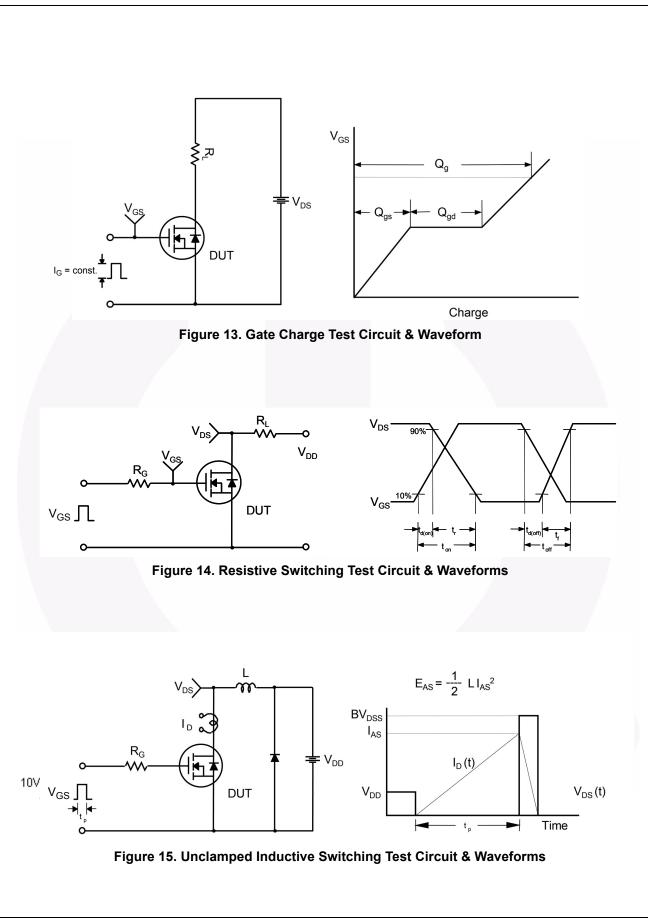
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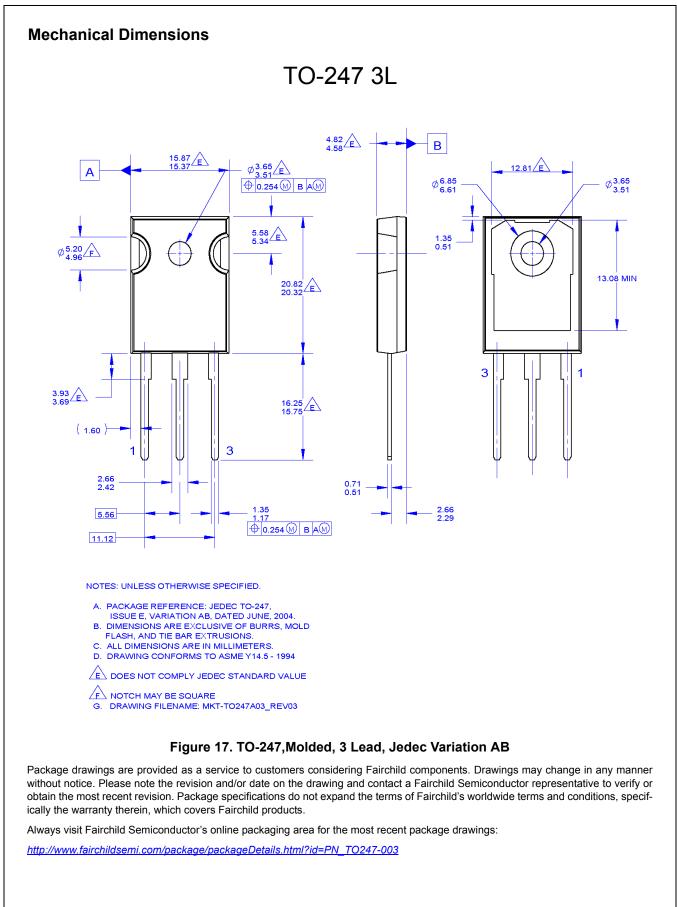
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FCH170N60 — N-Channel SuperFET[®] II MOSFET

DUT + V_{DS} I_{SD} L Driver R_G Same Type as DUT **≑** ∨_{DD} ∏∏ v_{gs} • dv/dt controlled by R_G • I_{SD} controlled by pulse period C Î Gate Pulse Width V_{GS} D = Gate Pulse Period 10V (Driver) I_{FM}, Body Diode Forward Current I _{SD} di/dt (DUT) I_{RM} Body Diode Reverse Current V_{DS} (DUT) Body Diode Recovery dv/dt V_{DD} V_{SD} Body Diode Forward Voltage Drop Figure 16. Peak Diode Recovery dv/dt Test Circuit & Waveforms





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